

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/738,397	JIN ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

SEARCHED						
Class	Subclass	Date	Examiner			
438	705	8/7/2006	вт			
438	724	8/7/2006	вт			
438	744	8/7/2006	вт			
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
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